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Nadeau-Dostie et al.

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(54) METHOD AND PROGRAM PRODUCT FOR MODELING CIRCUITS WITH LATCH BASED DESIGN

(76) Inventors: Benoit Nadeau-Dostie, 17 Croissant de

la Paix, Aylmer, Quebec (CA), J9H 3X7; Fadi Maamari, 1038 Camino Ricardo, San Jose, CA (US) 95125; Dwayne Burek, 5649 Le Fevre Dr., San Jose, CA (US) 05118

San Jose, CA (US) 95118

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Primary Examiner—Timothy P. Callahan Assistant Examiner—Cassandra Cox

(74) Attorney, Agent, or Firm—Eugene E. Proulx

(57) ABSTRACT

A method of and computer program product for modeling a logic circuit having combinational logic and latches, in which the latches are clocked by one of a first clock phase, a second clock phase or a pulse derived from the second clock phase, a subset of latches being scannable, comprises, for each latch in the logic circuit, associating the latch with one of the first and second clock phase; and when latch is associated with the first clock phase, modeling the latch as a buffer connected between the data input and output of latch; and when the latch is associated with the second clock phase, modeling the latch as an edge-triggered flip-flop having the same data input, data output and clock input as the latch.

25 Claims, 4 Drawing Sheets

